

2024 14th International Workshop on the Electromagnetic Compatibility of Integrated Circuits (EMC Compo 2024)

**Torino, Italy
7-9 October 2024**



**IEEE Catalog Number: CFP2448P-POD
ISBN: 979-8-3315-0464-9**

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IEEE Catalog Number:	CFP2448P-POD
ISBN (Print-On-Demand):	979-8-3315-0464-9
ISBN (Online):	979-8-3315-0463-2
ISSN:	2378-8224

Additional Copies of This Publication Are Available From:

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